



PBGA & QFN

FCBGA/3D Stack TC/TSC Evaluation

by

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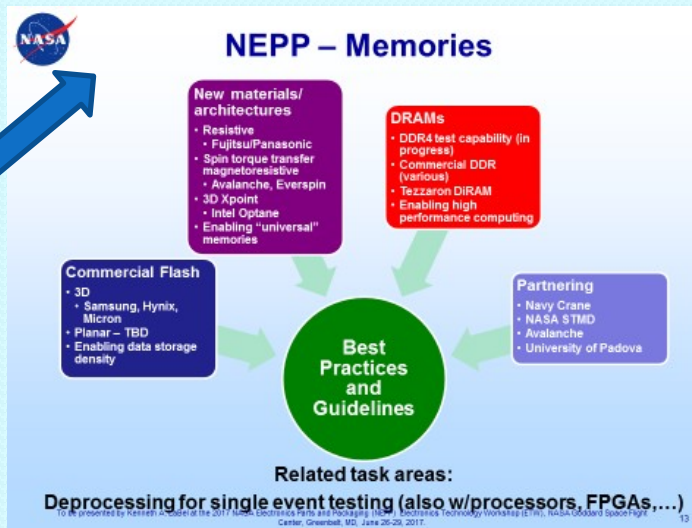
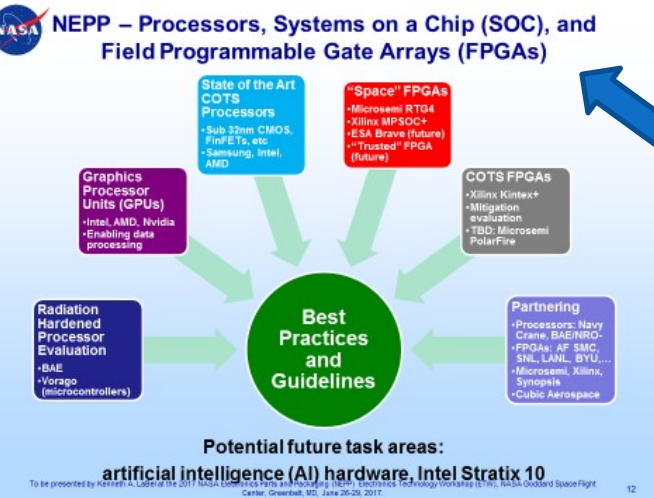
**NEPP Electronics Technology Workshop (ETW 2017)
June 26-29,2017, NASA GSFC**

<http://nepp.nasa.gov>



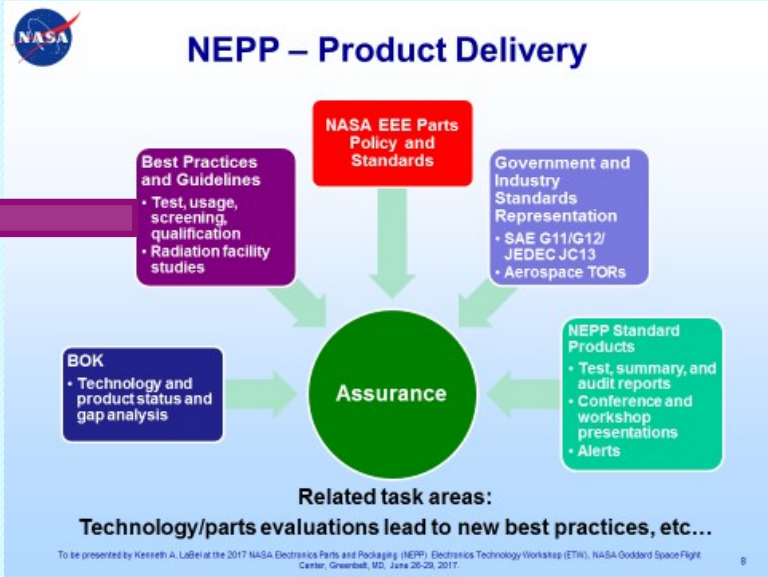
- PBGA TC Evaluation
 - Numerous BGA packages
 - WLP assembly challenge
 - Standard 3D stack
 - High I/O flip chip BGA, 2.5D (passive interposer)
 - Accelerated testing/failure mechanisms
 - PCB finish effect
- QFN evaluation
 - Various QFN package sizes
 - Effect of conformal coating
 - Accelerated TSC/TC testing
- TMV/2.5D/TSV
 - TMV test vehicle and build
 - Interposer 2.5D test vehicle build
 - TSV daisy-chain test approach

Guideline with Test Results NEPP Website



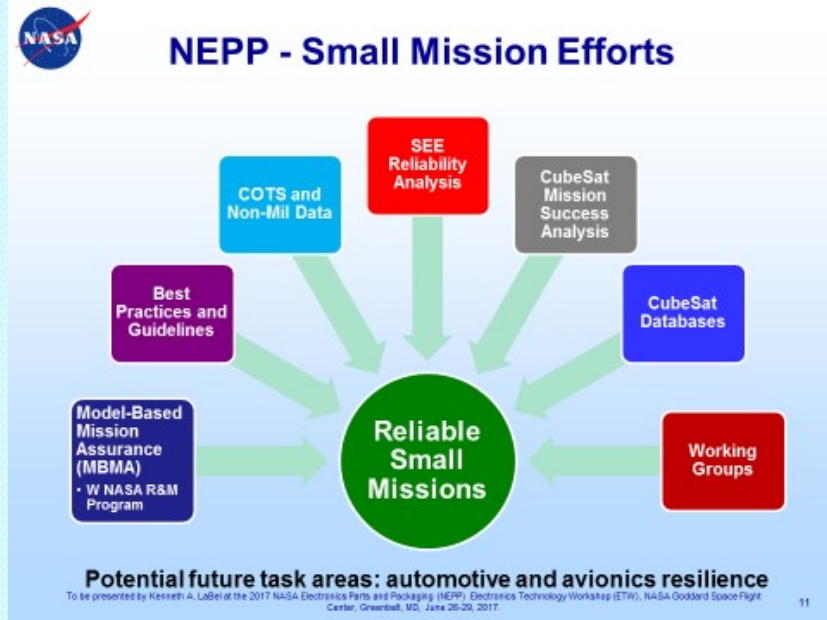
Best Practices and Guidelines

- Test, usage, screening, qualification
- Radiation facility studies



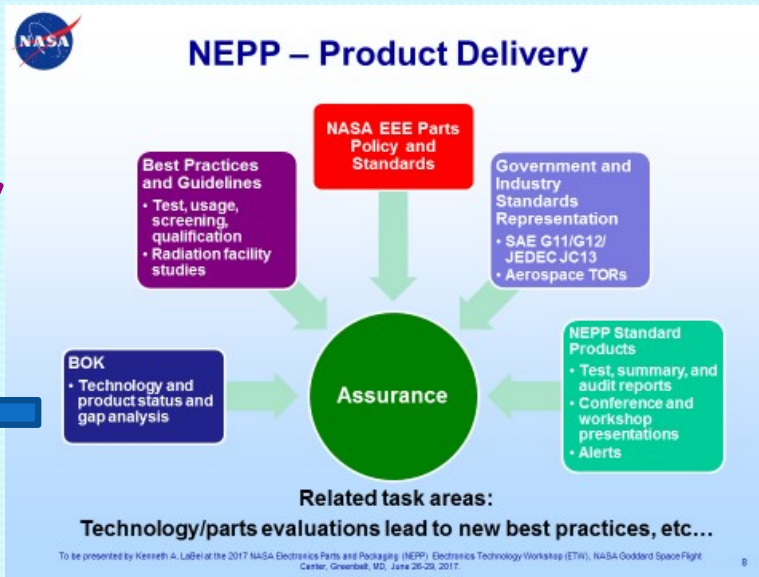
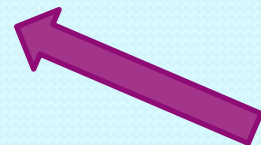
QFN TC Reliability

BOK
Guideline
Test Results
NEPP
Website



Best Practices and Guidelines

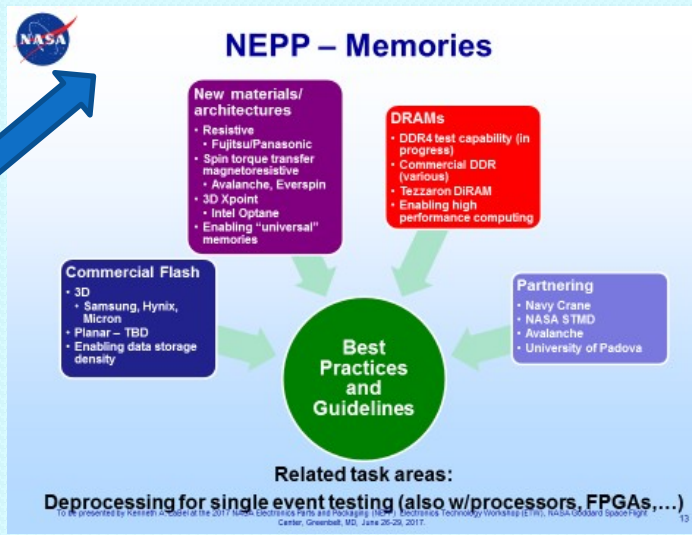
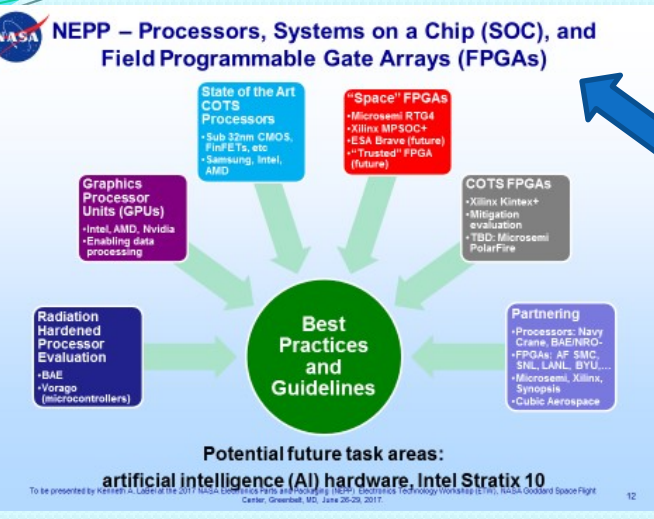
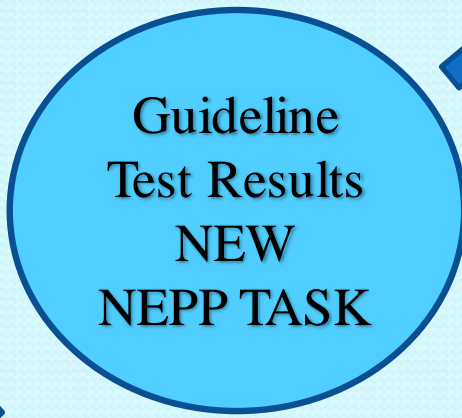
- Test, usage, screening, qualification
- Radiation facility studies



BOK

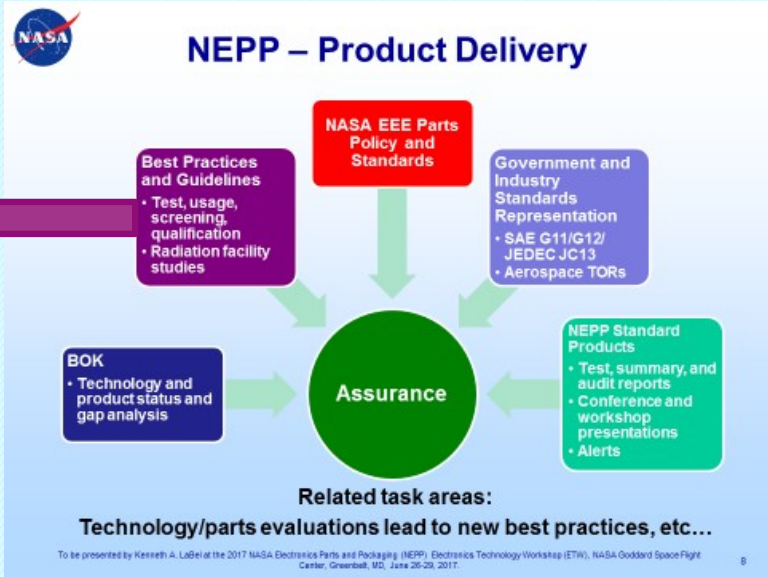
- Technology and product status and gap analysis





Best Practices and Guidelines

- Test, usage, screening, qualification
- Radiation facility studies





- Reliability
 - FCBGA/PBGA/WLP
 - 3D stack
- PCB Finish
 - HASL for SnPb
 - ENENIG for WLP and FPGA
- Reliability Results
 - 200 Thermal cycles
 - 200 Thermal shock cycles
 - X-ray, optical & X-section/SEM images
- Summary



PBGA/3D Stack Packages

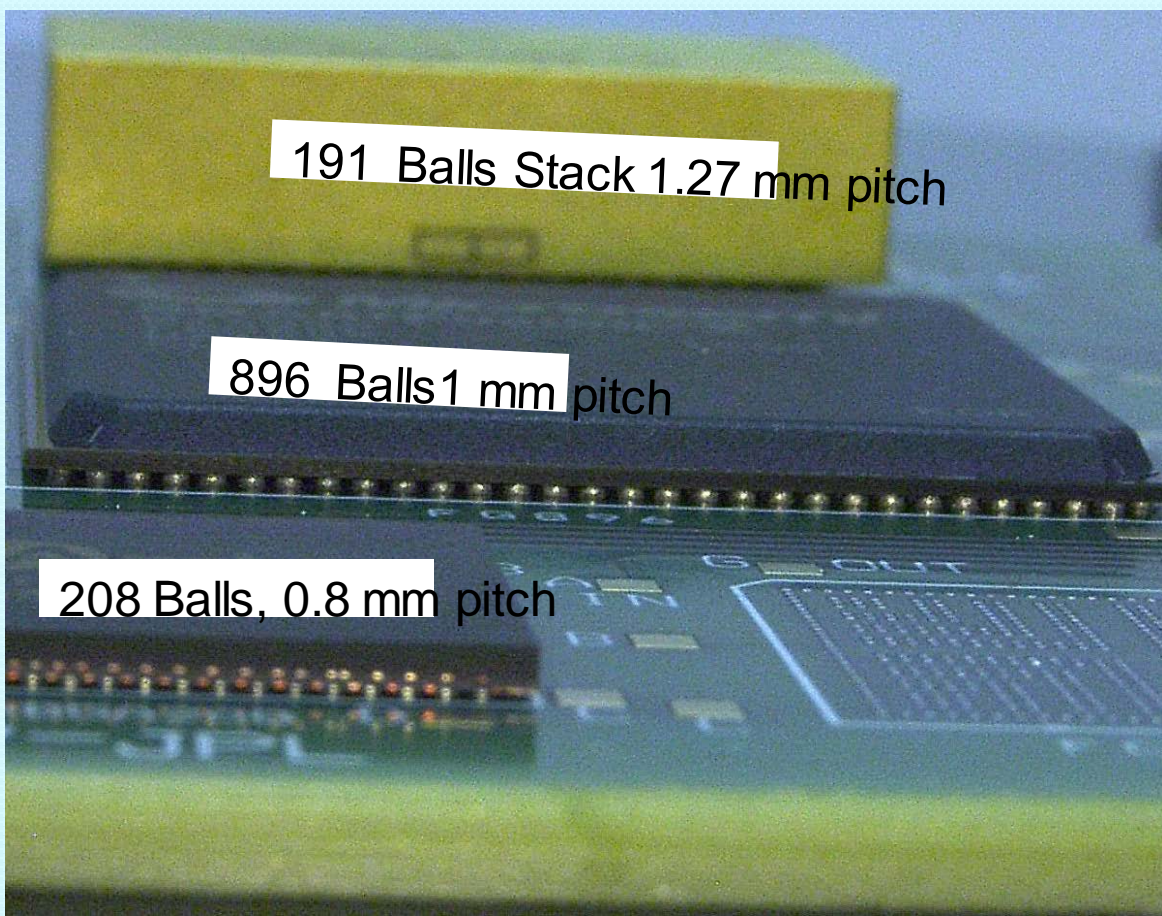
- Designed test matrix
- Select high I/O PBGA/FCBGAs and FPGA & 3D stack daisy-chain package for solder joint reliability and monitoring
- Selected two PCB finish (HASL/ENEPIG) with traces either on top or one layer under with microvia interconnections
- Successfully assembled TVs both single- and double- sided
- Performed QA evaluation followed by reliability testing
- Performed 200 TC ($-55^{\circ}\text{C}/100^{\circ}\text{C}$) or 200TSC ($-65^{\circ}\text{C}/150^{\circ}\text{C}$)





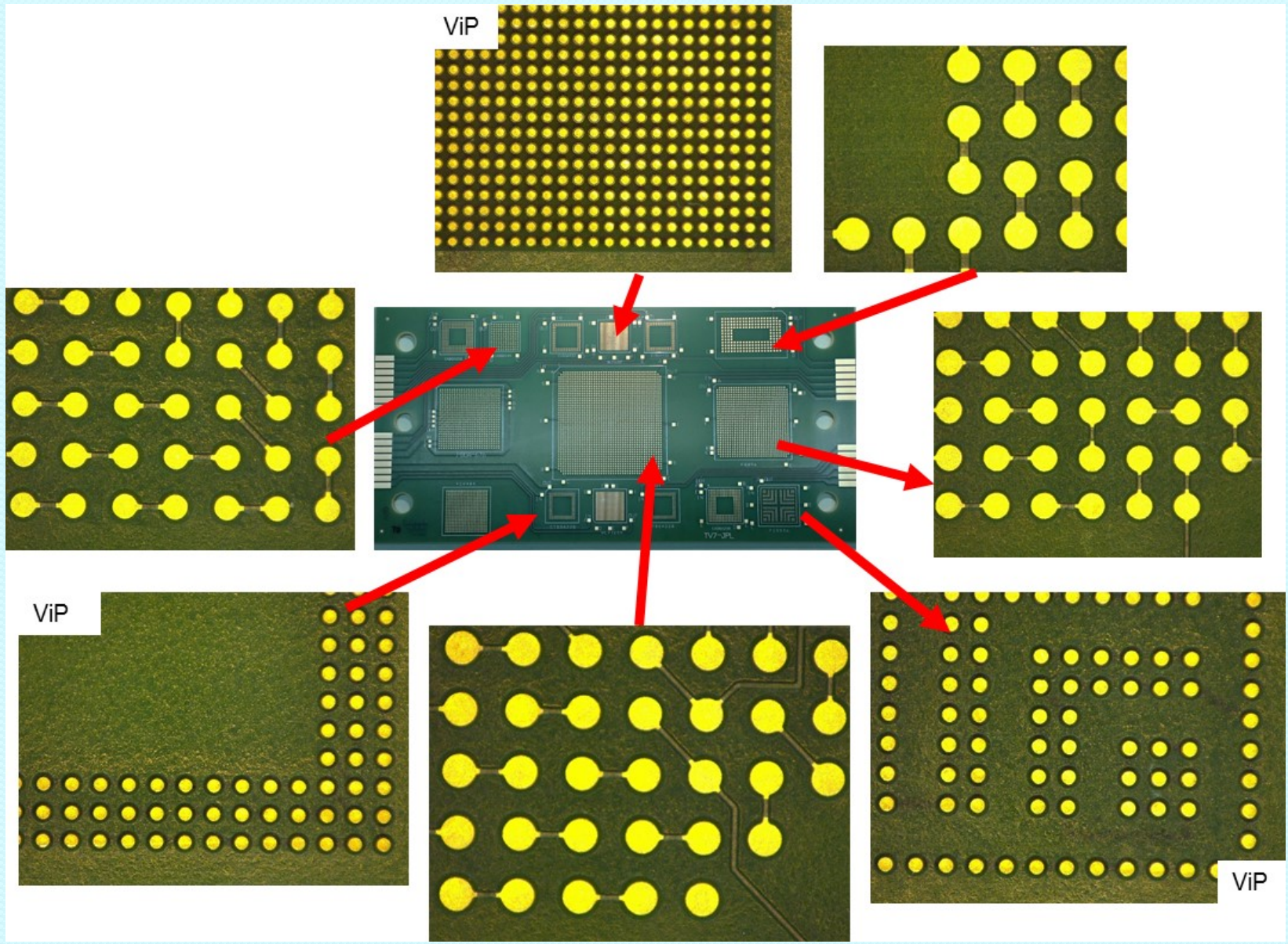
PBGAs/3D Stack

- PBGA pitch from 0.4 mm to 1.27 mm
- 3D stack, 1mm pitch
- WLP, 1600 balls, 0.3 mm pitch



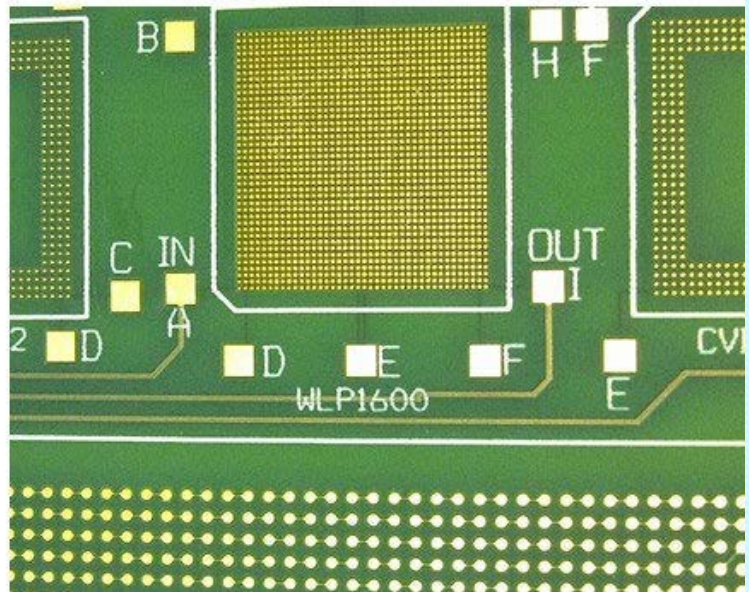
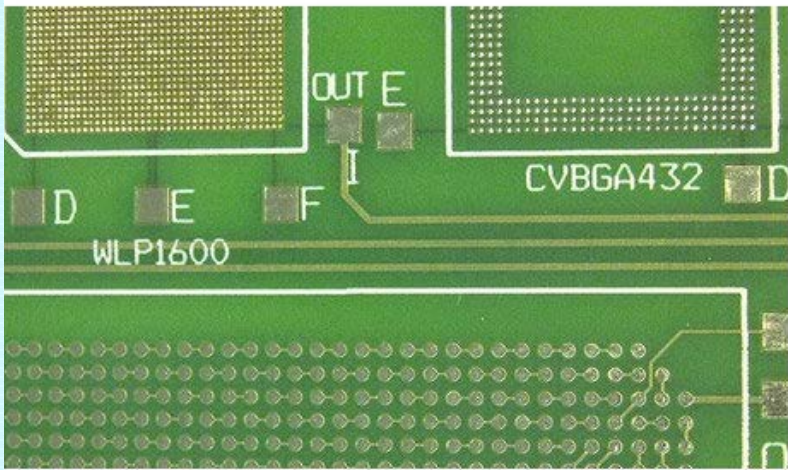
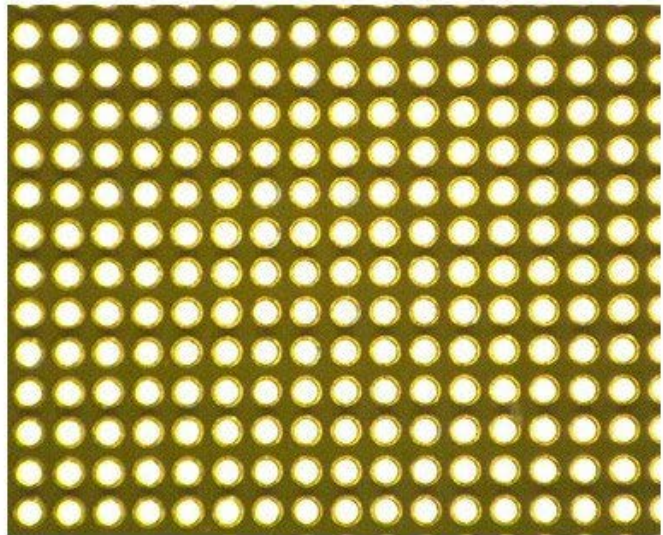
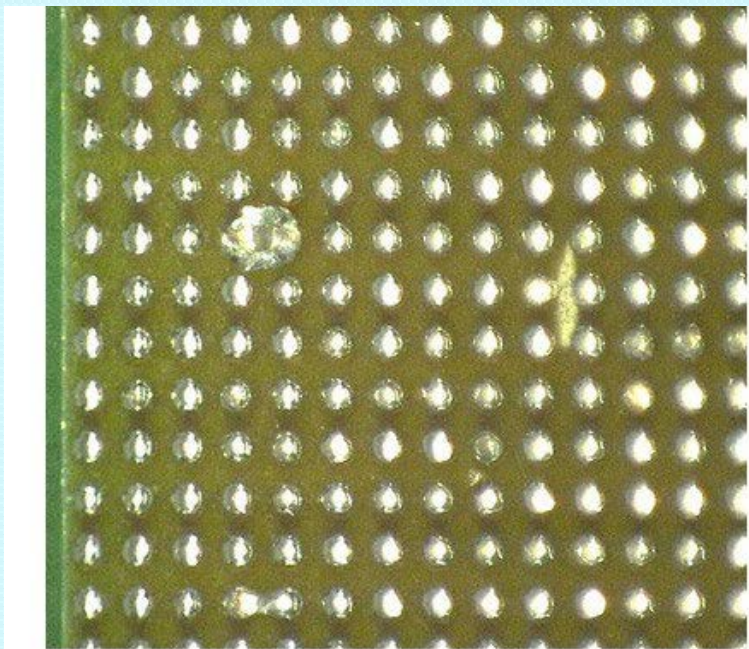


PCB Design



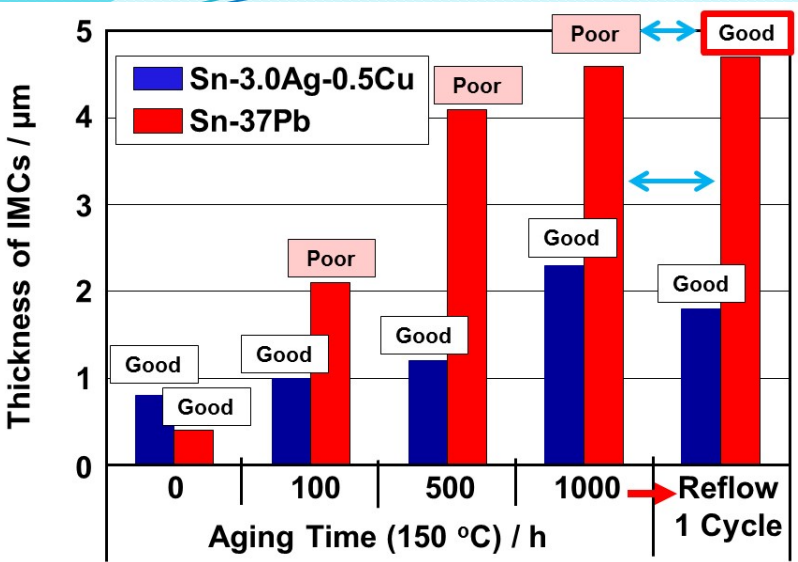


HASL vs ENEPIG





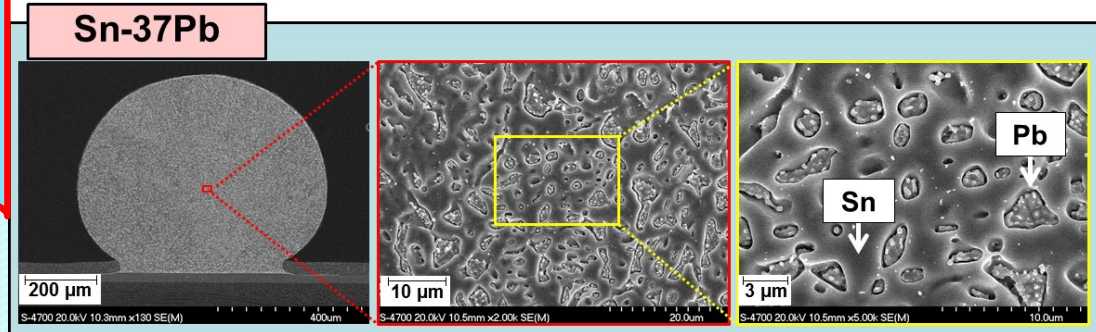
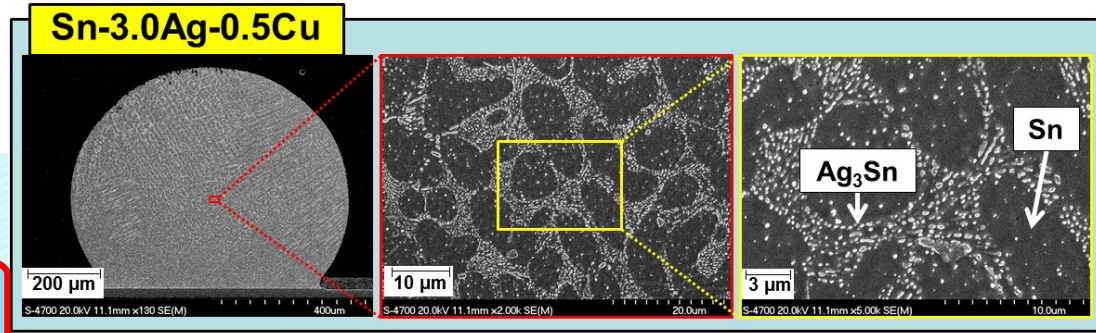
SnPb or SAC on ENEPIG



Growth Rate of IMCs
Sn-37Pb > Sn-3.0Ag-0.5Cu

A PCB with “corrosion spikes” on Ni layer.
The IMC layer spalled off
Tegehall-ESA

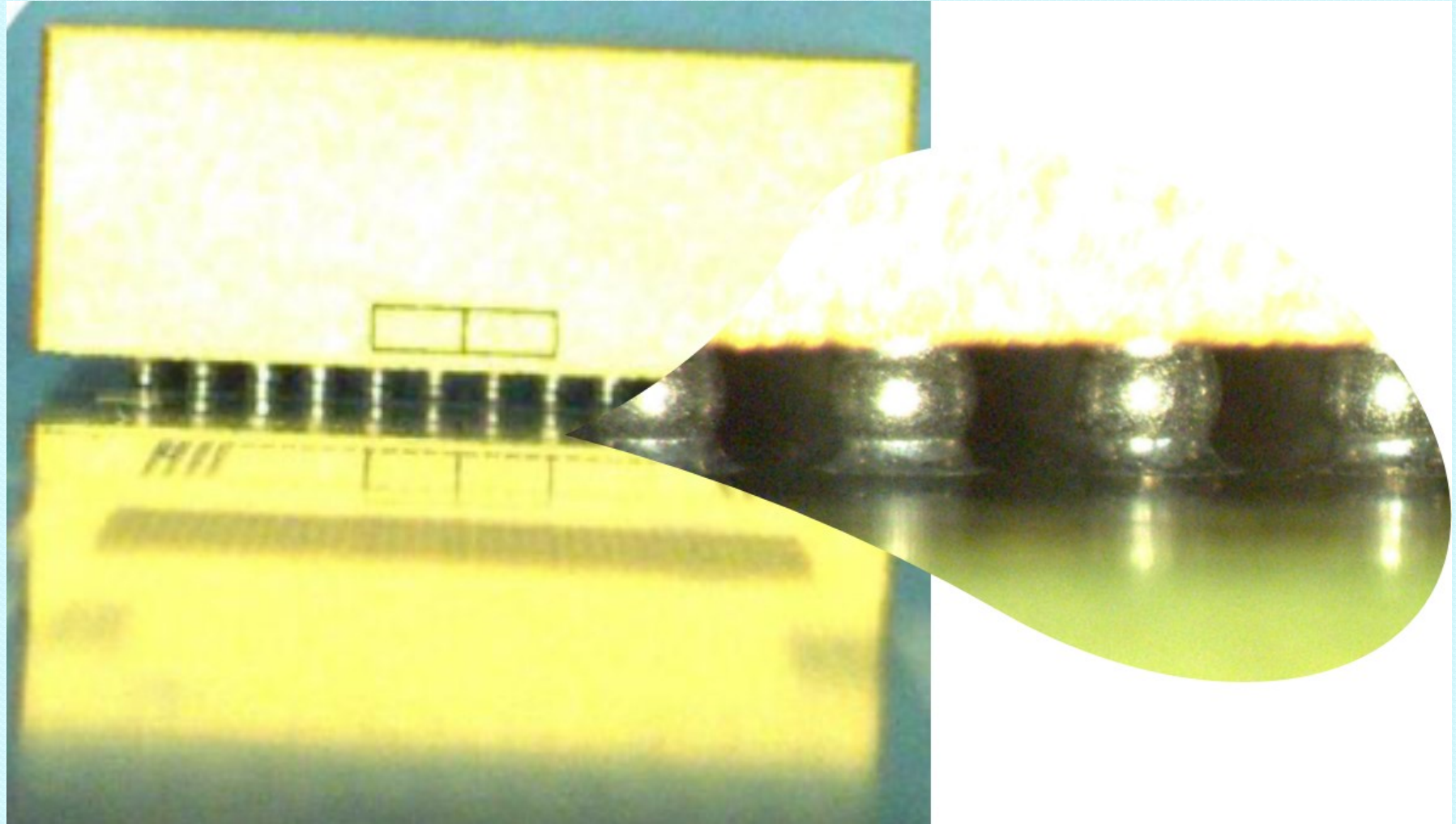
ENEPIG/SnPb is NOT recommended for high T use
Milad-Uyemura





3D Stack

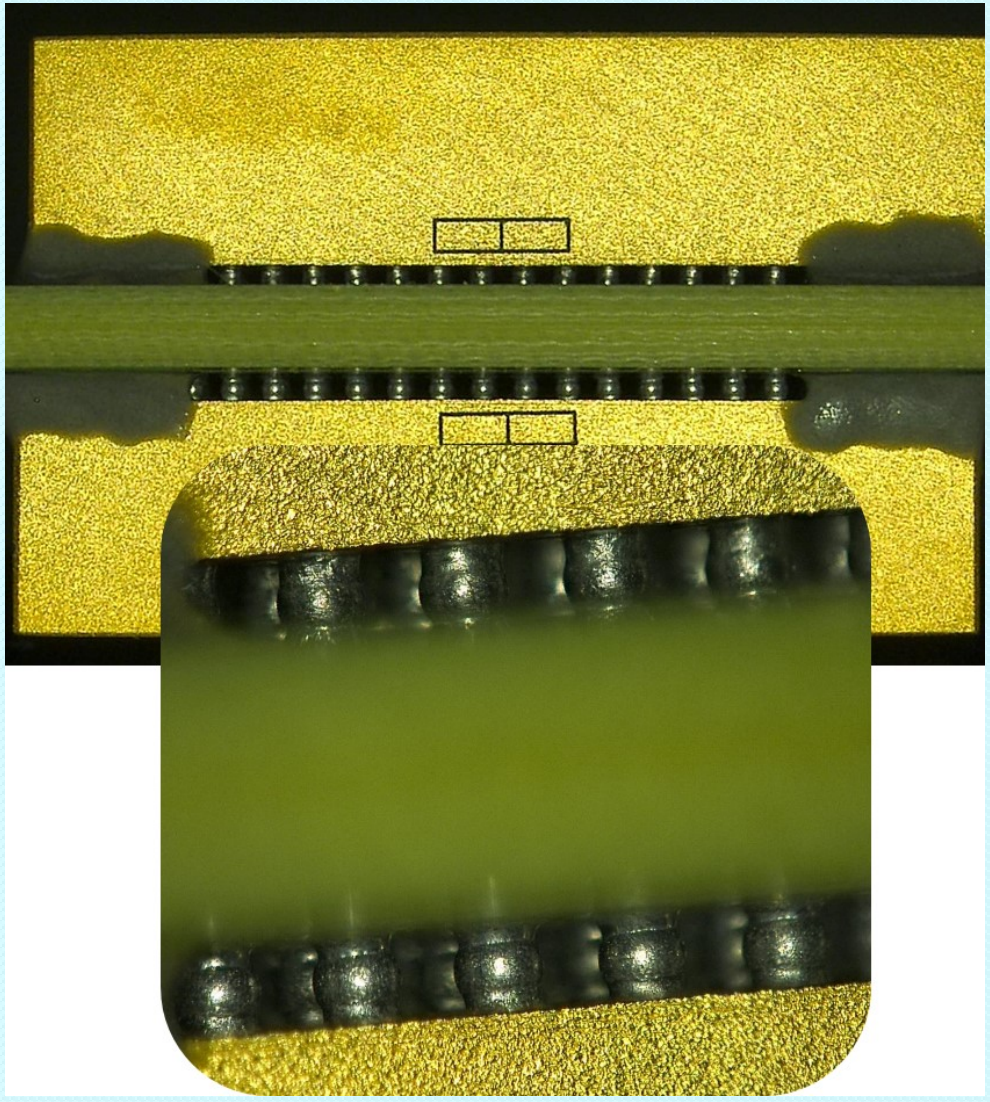
Single-sided





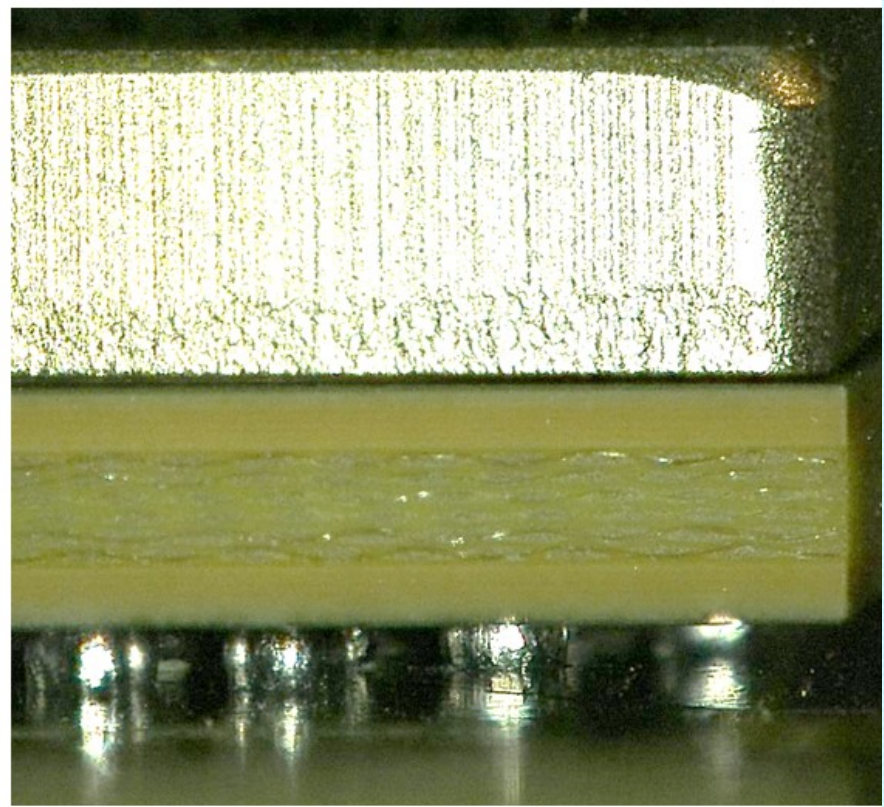
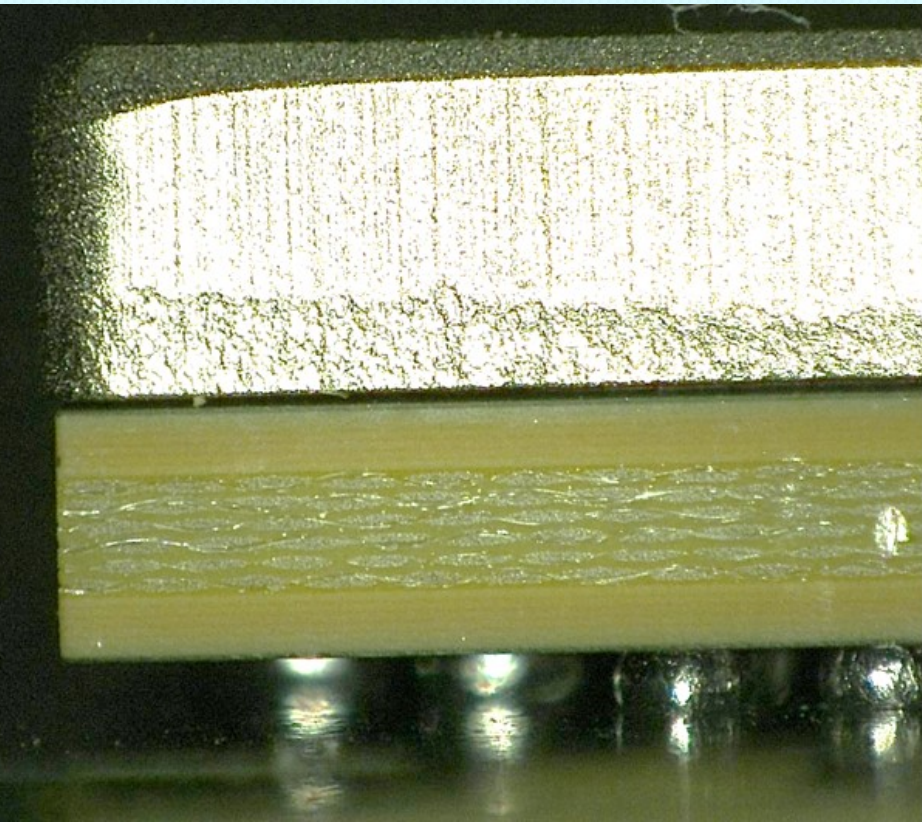
3D Stack

Double-sided





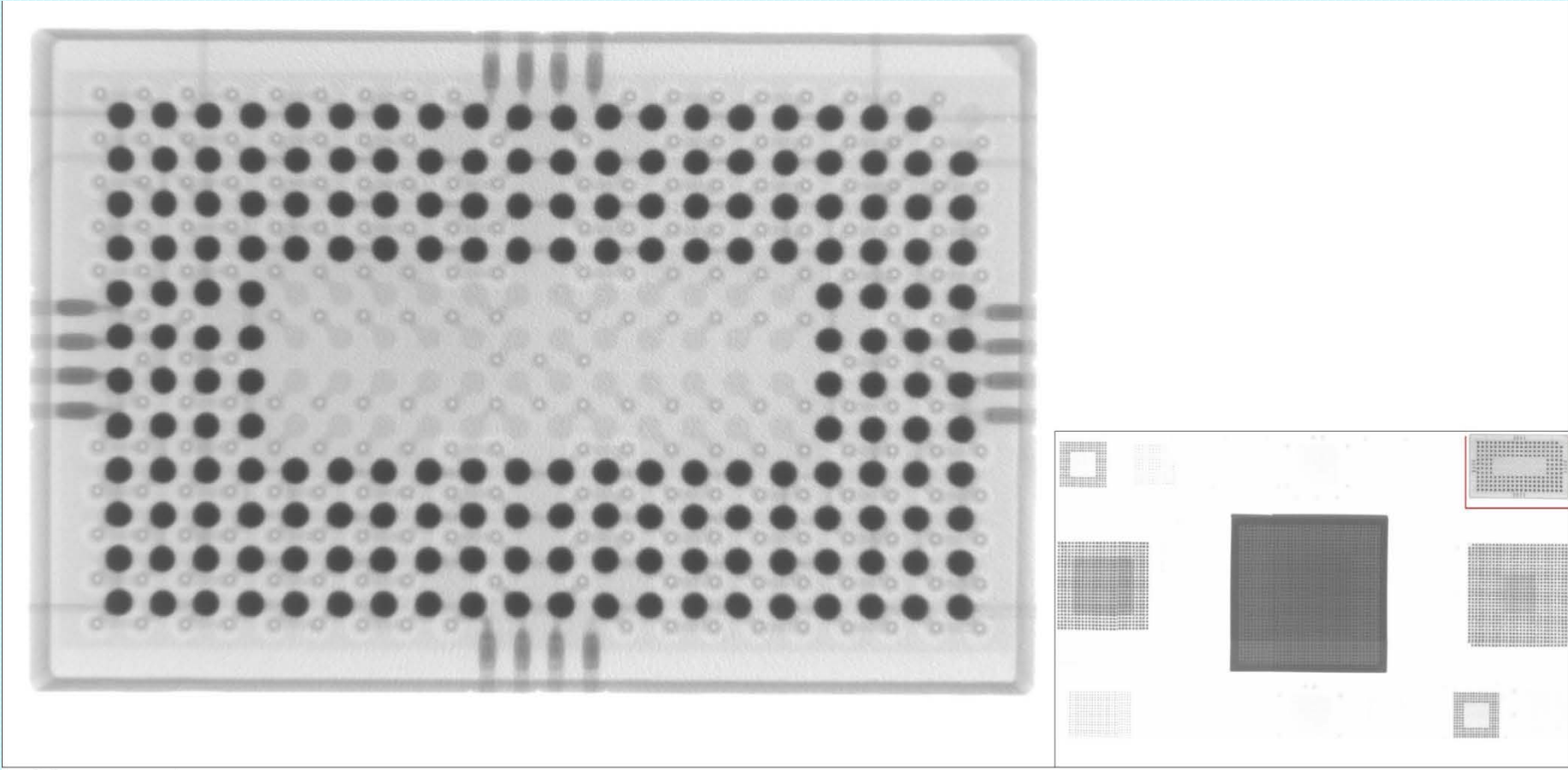
FCBGA 1924



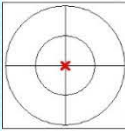


X-ray 3D Stack

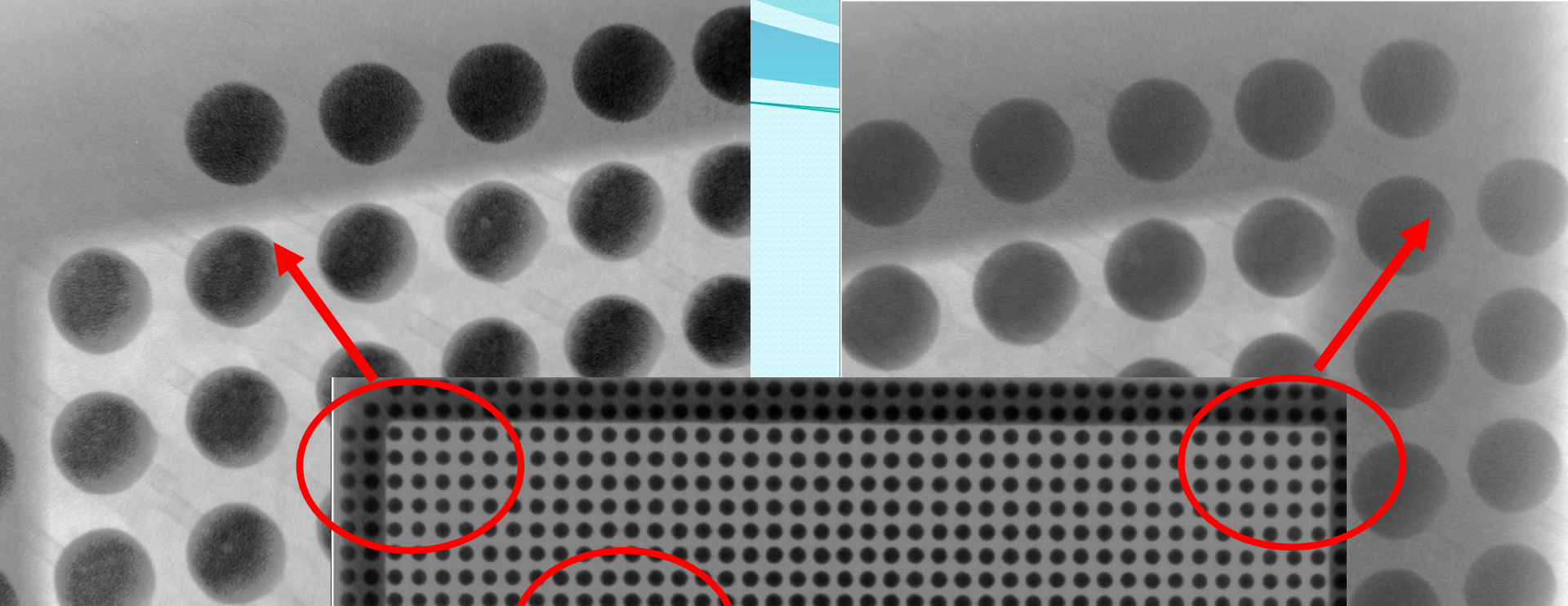
Single-sided



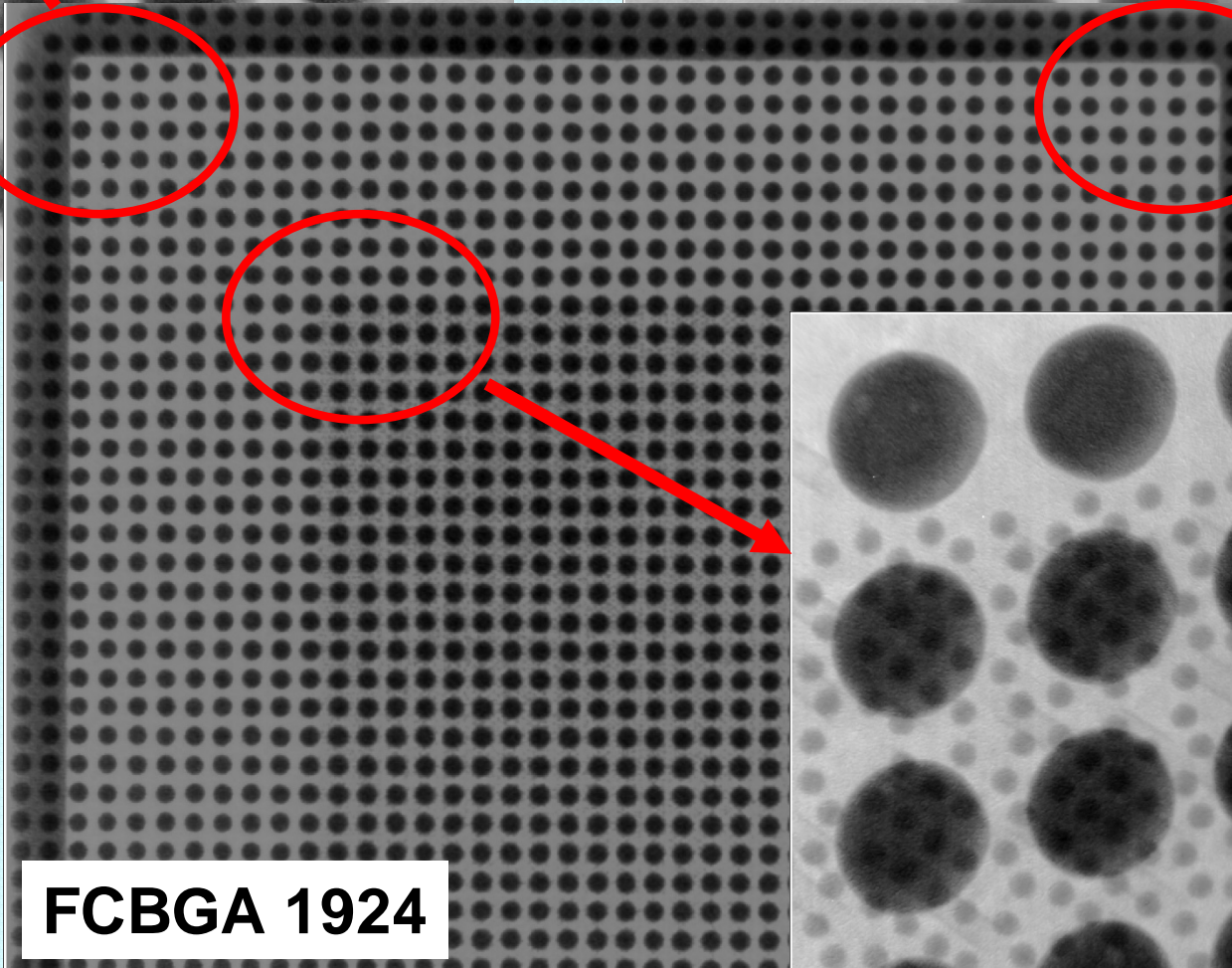
5.0mm



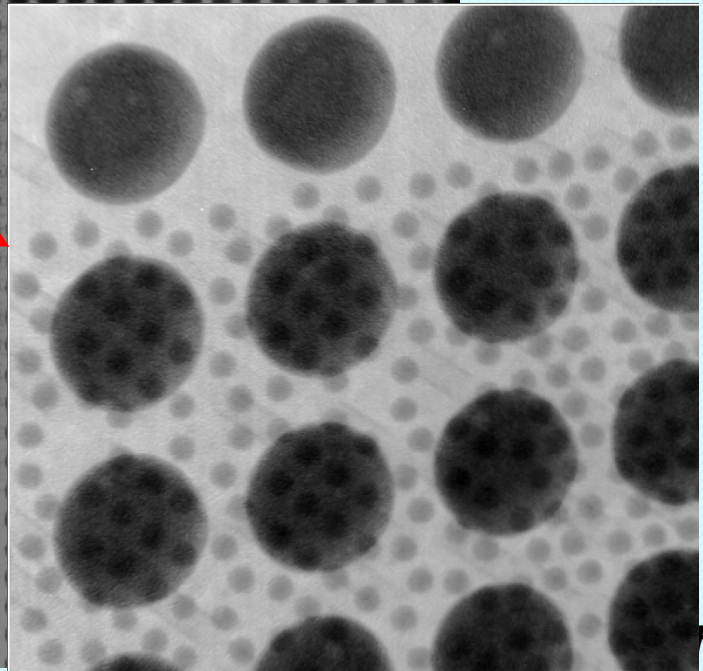
Tube voltage: 105 kV
Tube power: 1.98 W
Filter method used: None
Averaging: 64 frames



**X-ray
FCBGA
1924 I/O**



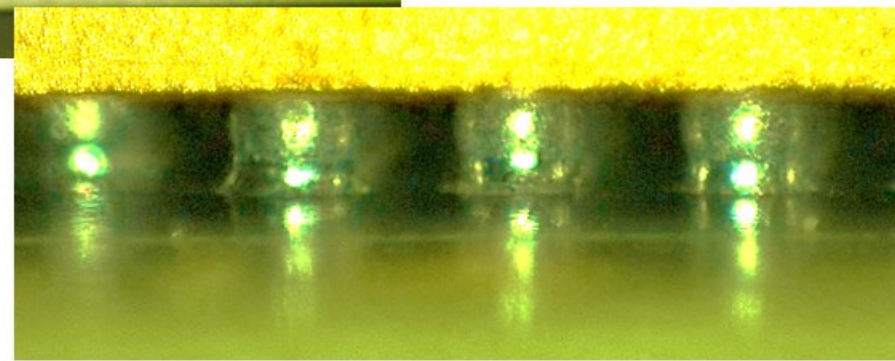
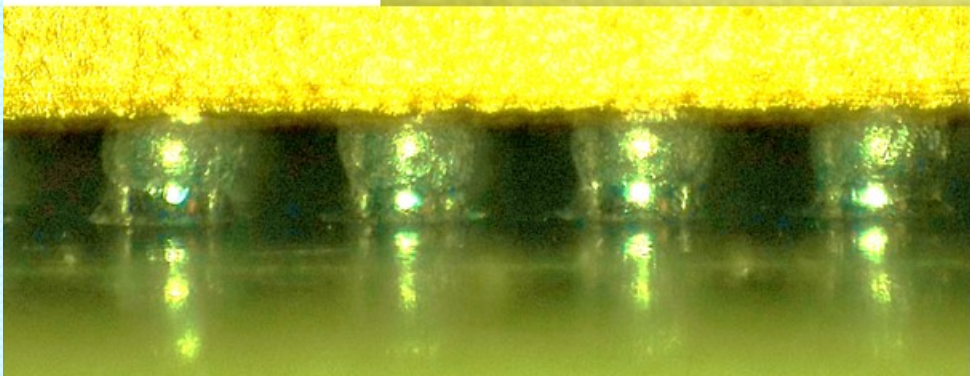
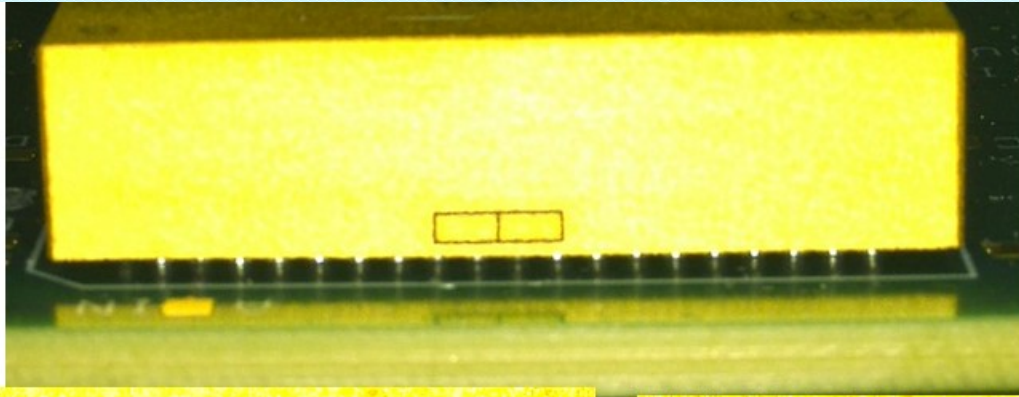
FCBGA 1924





3D Stack

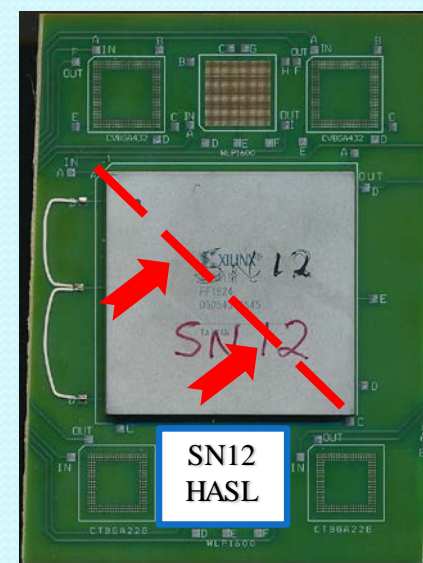
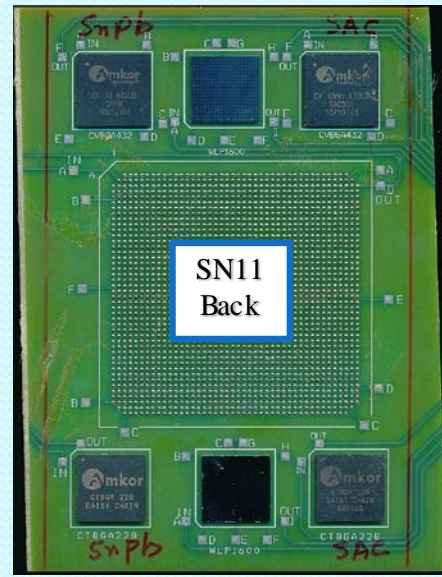
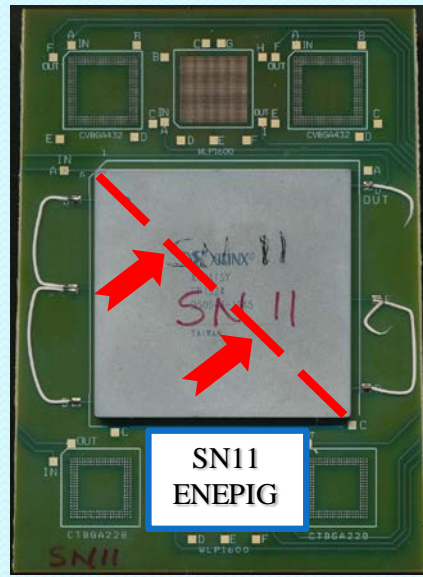
200TC (-55°C/100°C)





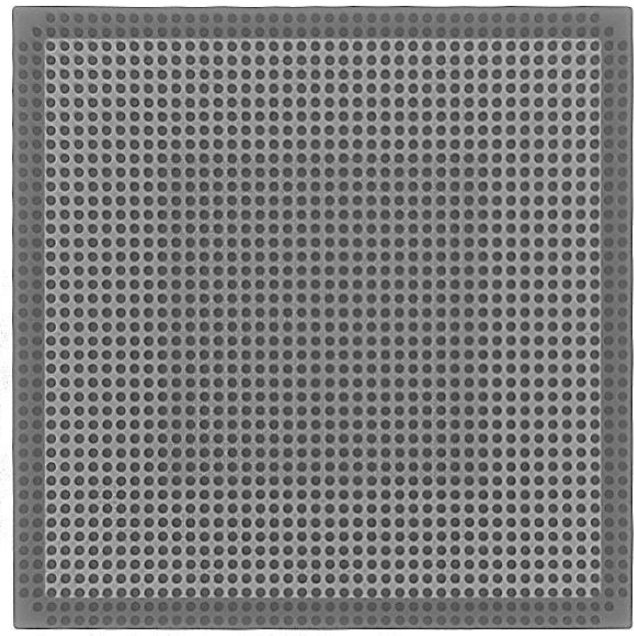
FCBGA 1924

200 TSC(-65°C/150°C)

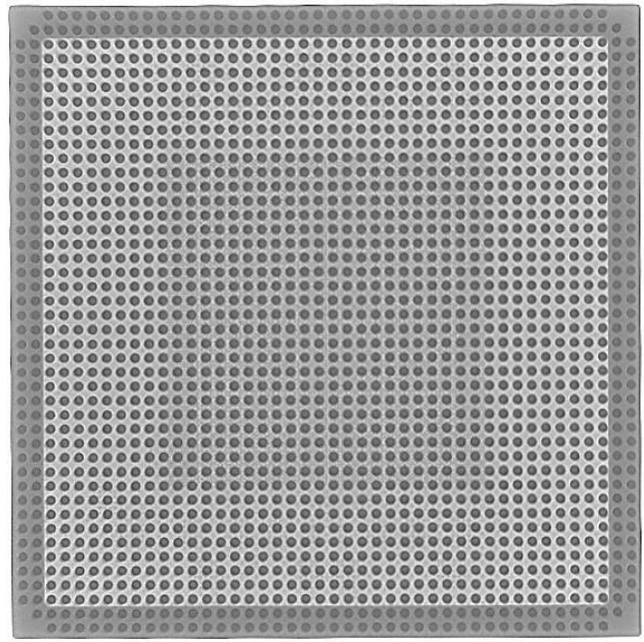
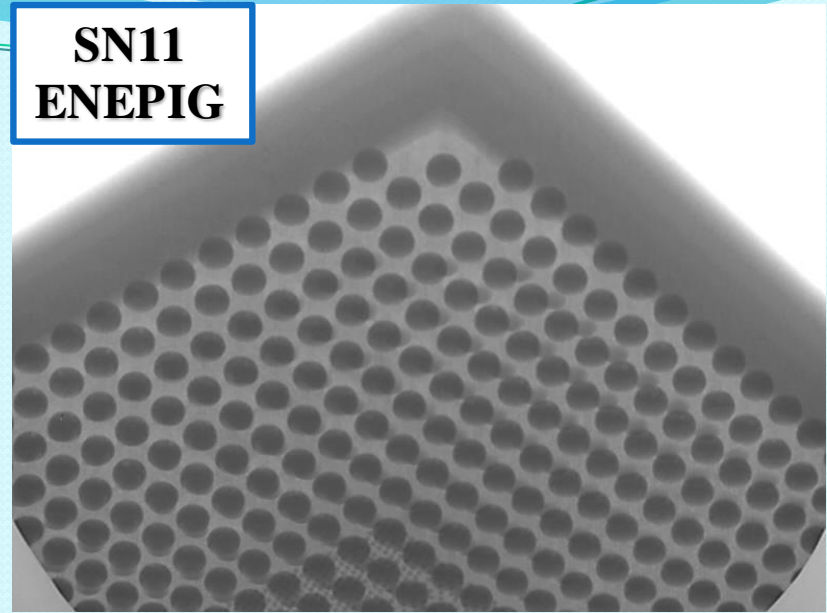




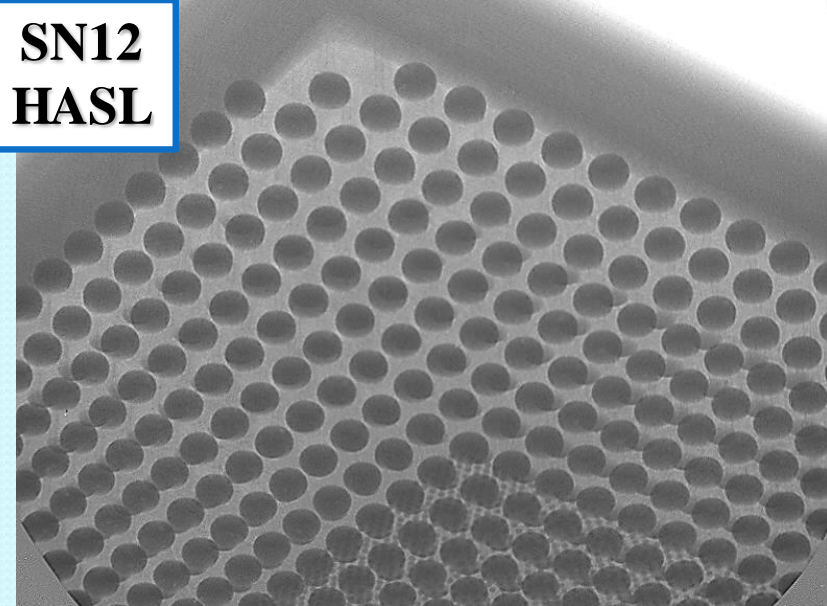
X-ray FCBGA 1924



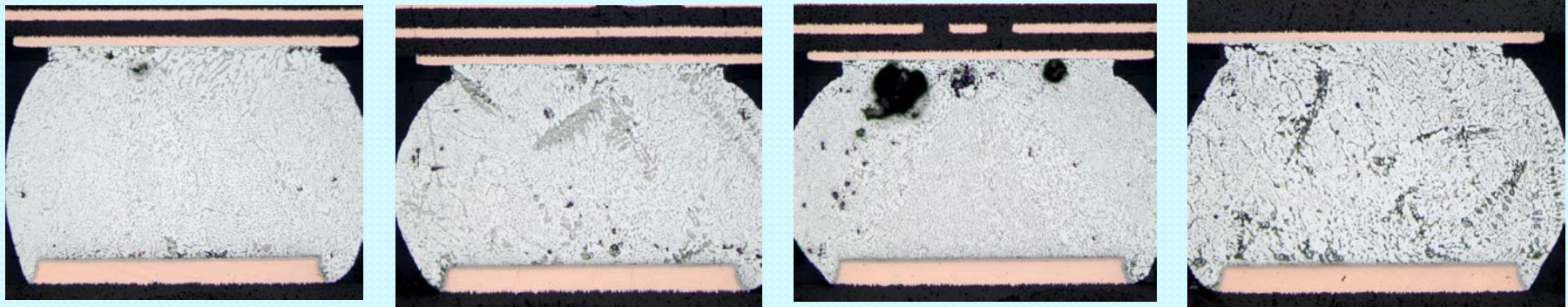
**SN11
ENEPIG**



**SN12
HASL**

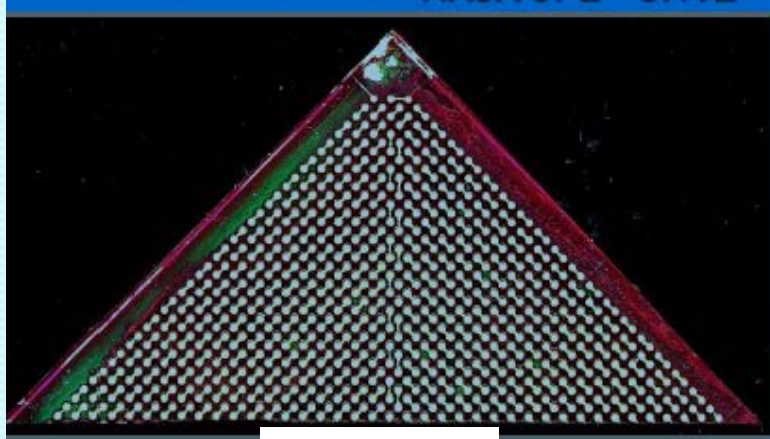


FCBGA 1924 on ENEPIG 200 TS (-65/150°C)

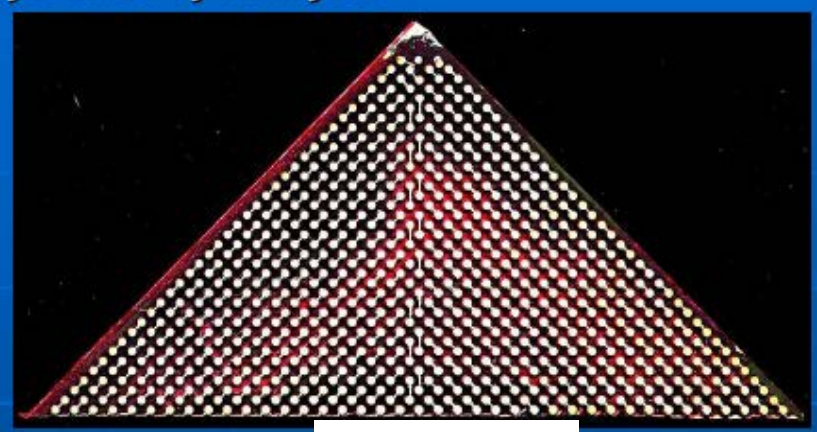


FCBGA 1924 on HASL

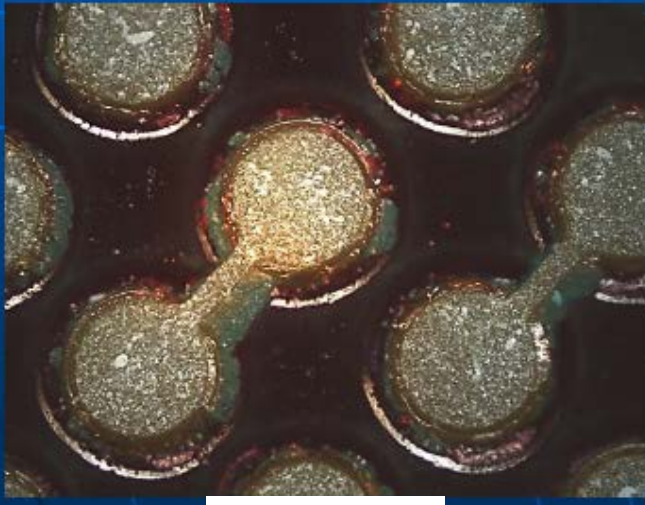
200 TSC (-65°C/150°C)



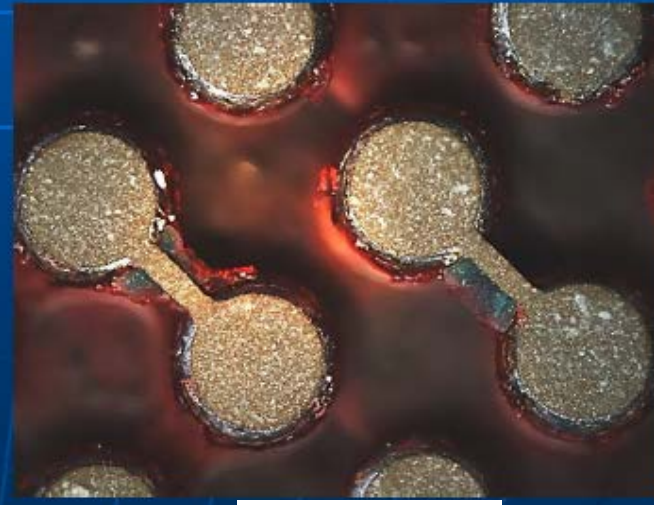
PCB Pads



BGA Pads



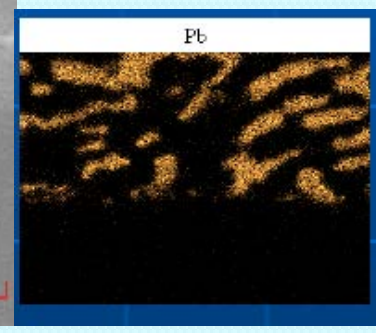
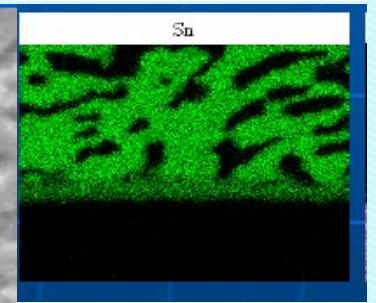
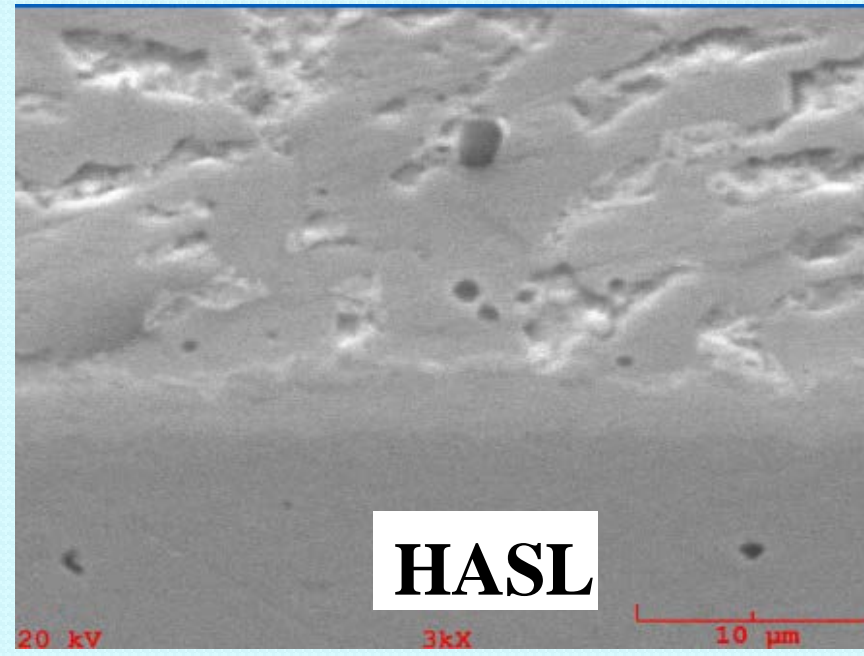
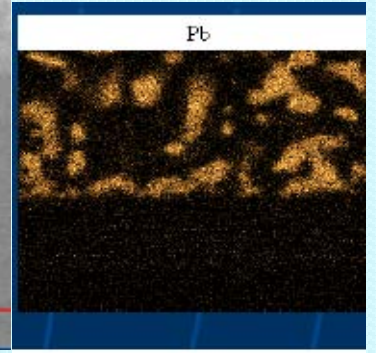
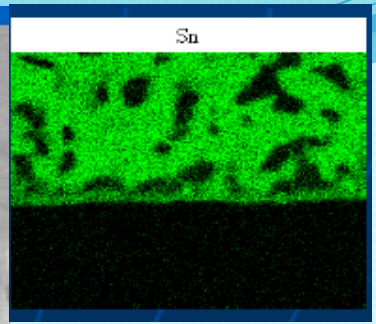
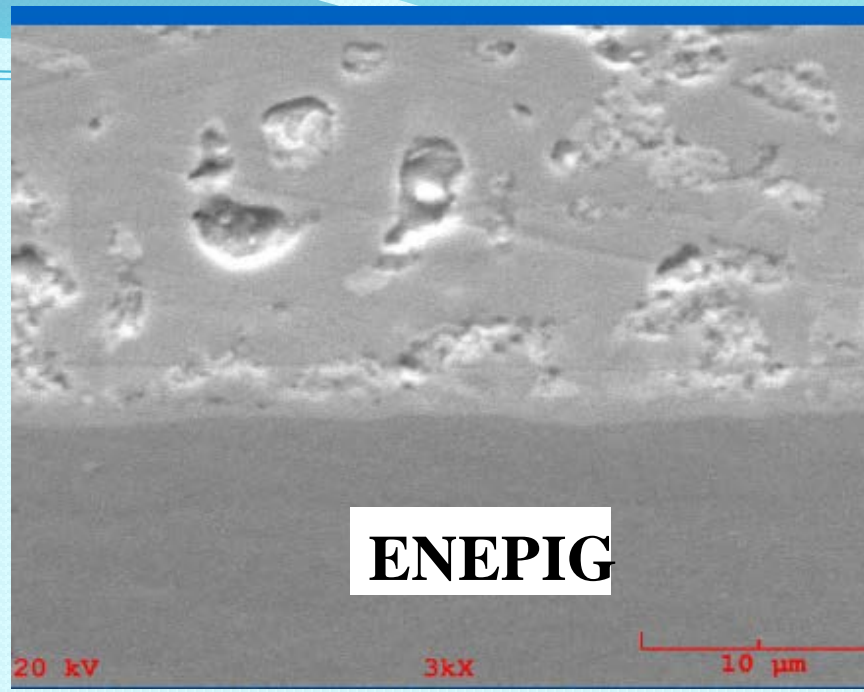
PCB Pads



BGA Pads

No defective solder connections were found.

**SEM/EDS
FCBGA
1924
ENEPIG
HASL**





- Released NEPP report
 - <https://nepp.nasa.gov/>
 - Evaluated FCBGA, FPBGA, 3D Stack, and more
 - PCB finish
 - HASL/ENEPIG
- 3D Stack/FPBGA1924
 - 200 TC (-55°C/125°C) on ENEPIG
 - No failures of 3D stack/FCBGA
 - 200 TSC (- 65°C/150°C)
 - No failure of FCBGA 1924
 - Failure of FPBGA from package sites
- Evaluate further when funded



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<http://nepp.nasa.gov>

**Thank
You!**

